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Application/Control No.	Applicant(s)/Patent under Reexamination
10/665,849	KRIS ET AL.
Examiner	Art Unit

Yuzhen Ge

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EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout	DATE  12/5/2006  12/5/2006	YG
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout  IEEE Xplore - See search session history printout	12/5/2006	
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